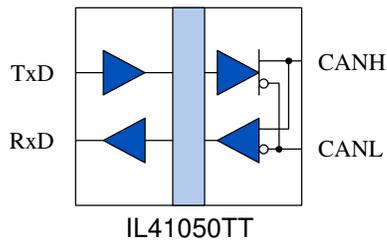


Basic Function Isolated CAN Transceiver

Functional Diagram



V _{DD2} (V)	TxD ⁽¹⁾	S	CANH	CANL	Bus State	RxD
4.75 to 5.25	↓	Low ⁽²⁾	High	Low	Dominant	Low
4.75 to 5.25	X	High	V _{DD2} /2	V _{DD2} /2	Recessive	High
4.75 to 5.25	↑	X	V _{DD2} /2	V _{DD2} /2	Recessive	High
<2V (no pwr)	X	X	0<V<2.5	0<V<2.5	Recessive	High
2<V _{DD2} <4.75	>2V	X	0<V<2.5	0<V<2.5	Recessive	High

Table 1. Function table.

Notes:

1. TxD input is edge triggered: ↑ = Logic Lo to Hi, ↓ = Hi to Lo
 2. Valid for logic state as described or open circuit
- X = don't care

Features

- Industry-standard pinout
- 5000 V_{RMS} isolation (IL41050TTVE)
- 180 ns typical loop delay
- 70 mA maximum bus-side dynamic supply current
- 12 mA maximum quiescent recessive supply current
- 1 Mbps
- Fully compliant with the ISO 11898-2 CAN standard
- -55 °C to 100 °C operating temperature
- 3 V to 5.5 V power supplies
- >110-node fan-out
- 44000-year barrier life
- ±500 V CDM ESD
- 50 kV/μs typ.; 30 kV/μs min. common mode transient immunity
- No carrier or clock for low emissions and EMI susceptibility
- Transmit data (TxD) dominant time-out function
- Edge triggered, non-volatile input improves noise performance
- Thermal shutdown protection
- Bus power short-circuit protection
- No "S" or Vref functions
- IEC 60747-17 (VDE 0884-17):2021-10 certified; UL 1577 recognized
- 0.3" True 8™ mm 16-pin packages



Applications

- Factory automation
- Battery management systems
- Noise-critical CAN
- DeviceNet

Description

The IL41050TT is a galvanically isolated, CAN (Controller Area Network) transceiver containing basic functions but without "S" or Vref pins. It is a direct replacement for the Texas Instruments ISO1050DW with much better reliability and longer barrier life, less EMI emissions, and true 8 mm external creepage.

The IL41050 family provides isolated differential transmit capability to the bus and isolated differential receive capability to the CAN controller via NVE's patented* spintronic Giant Magnetoresistance (GMR) technology.

A unique ceramic/polymer composite barrier provides excellent isolation and virtually unlimited barrier life.

Designed for harsh CAN and DeviceNet environments, IL41050 transceivers have transmit data dominant time-out, bus pin transient protection, a rugged Charged Device Model ESD rating, thermal shutdown protection, and short-circuit protection. Unique edge-triggered inputs improve noise performance.

Absolute Maximum Ratings⁽¹⁾⁽²⁾

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Storage temperature	T_S	-55		150	°C	
Junction temperature	T_J	-55		150	°C	
DC voltage at CANH and CANL pins	V_{CANH}, V_{CANL}	-45		45	V	0 V < V_{DD2} < 5.25 V; indefinite duration
Supply voltage	V_{DD1}, V_{DD2}	-0.3		7	V	
Digital input voltage	V_{TXD}, V_S	-0.3		$V_{DD} + 0.3$	V	
Digital output voltage	V_{RXD}	-0.3		$V_{DD} + 0.3$	V	
DC voltage at V_{REF}	V_{REF}	-0.3		$V_{DD} + 0.3$	V	
Transient voltage at CANH or CANL	$V_{tr(CAN)}$	-150		150	V	
Electrostatic discharge at all pins	V_{esd}	-4000		4000	V	Human body model
Electrostatic discharge at all pins	V_{esd}	-500		500	V	Machine model

Recommended Operating Conditions

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Supply voltage	V_{DD1}	3.0		5.5	V	
	V_{DD2}	4.75		5.25		
Ambient operating temperature	T_A	-55		110	°C	
Junction temperature	T_J	-55		110	°C	
Input voltage at any bus terminal (separately or common mode)	V_{CANH} V_{CANL}	-12		12	V	
High-level digital input voltage ⁽³⁾⁽⁴⁾	V_{IH}	2.0 2.4 2.0		V_{DD1} V_{DD1} V_{DD2}	V	$V_{DD1} = 3.3$ V $V_{DD1} = 5.0$ V $V_{DD2} = 5.0$ V
Low-level digital input voltage ⁽³⁾⁽⁴⁾	V_{IL}	0		0.8	V	
Digital output current (RxD)	I_{OH}	-8		8	mA	$V_{DD1} = 3.3$ V to 5 V
Ambient operating temperature	T_A	-55		100	°C	
Digital input signal rise and fall times	t_{IR}, t_{IF}			1	µs	

Safety and Approvals

IEC 60747-17 (VDE 0884-17):2021-10:

IL41050TTVE version (Reinforced Isolation; VDE File Number 5016933-4880-0002)

- Working Voltage (V_{IORM}): 600 V_{RMS} (850 V_{PK}) with 20% Safety Factor; pollution degree 2
- Isolation voltage (V_{ISO}): 5000 V_{RMS}
- Surge immunity (V_{IOSM}): 12.8 kV $_{PK}$
- Surge rating: 8000 V
- Transient overvoltage (V_{IOTM}): 6000 V_{PK}
- Each part tested at 1194 V_{PK} for 1 second, 5 pC partial discharge limit
- Samples tested at 5000 V_{PK} for 60 sec.; then 2122 V_{PK} for 10 sec. with 5 pC partial discharge limit

IL41050TTE version (Basic Isolation; VDE File Number 5016933-4880-0001)

- Isolation voltage (V_{ISO}): 2500 V_{RMS}
- Transient overvoltage (V_{IOTM}): 4000 V_{PK}
- Surge rating: 4000 V
- Each part tested at 1590 V_{PK} for 1 second, 5 pC partial discharge limit.
- Samples tested at 4000 V_{PK} for 60 sec.; then 1358 V_{PK} for 10 sec. with 5 pC partial discharge limit.
- Working Voltage (V_{IORM} ; pollution degree 2): 600 V_{RMS}

Safety-Limiting Values	Symbol	Value	Units
Safety rating ambient temperature	T_S	180	$^{\circ}C$
Safety rating power (180 $^{\circ}C$)	P_S	270	mW
Supply current safety rating (total of supplies)	I_S	54	mA

Soldering Profile

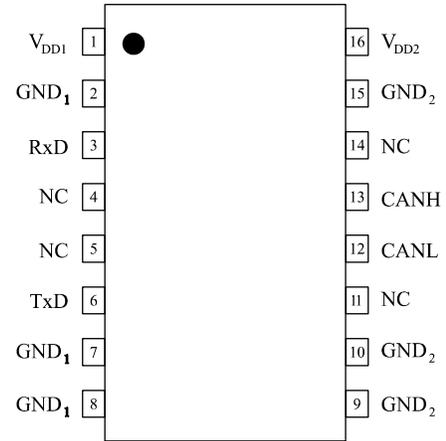
Per JEDEC J-STD-020C; MSL=1

Notes:

1. Absolute Maximum specifications mean the device will not be damaged if operated under these conditions. It does not guarantee performance.
2. All voltages are with respect to network ground except differential I/O bus voltages.
3. The TxD input is edge sensitive. Voltage magnitude of the input signal is specified, but edge rate specifications must also be met.
4. The maximum time allowed for a logic transition at the TxD input is 1 μs .

IL41050TT Pin Connections

1	V _{DD1}	V _{DD1} power supply input
2	GND ₁	V _{DD1} power supply ground return (pin 2 is internally connected to pin 8)
3	RxD	Receive Data output
4	NC	No internal connection
5	NC	No internal connection
6	TxD	Transmit Data input
7,8	GND ₁	V _{DD1} power supply ground return (pin 8 is internally connected to pin 2)
9,10	GND ₂	V _{DD2} power supply ground return (pin 9 is internally connected to pin 15)
11	NC	No internal connection
12	CANL	Low level CANbus line
13	CANH	High level CANbus line
14	NC	No internal connection
15	GND ₂	V _{DD2} power supply ground return (pin 15 is internally connected to pin 9)
16	V _{DD2}	V _{DD2} isolation power supply input



Operating Specifications

Electrical Specifications (T_{min} to T_{max} and V_{DD1} , $V_{DD2}= 4.75$ V to 5.25 V unless otherwise stated)						
Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Power Supply Current						
Quiescent supply current (recessive)	I_{QVDD1}	1 0.7	1.75 1.4	3.0 2.0	mA	$dr = 0$ bps; $V_{DD1} = 5$ V $dr = 0$ bps; $V_{DD1} = 3.3$ V
Dynamic supply current (dominant)	I_{VD1}	1.2 0.9	2.0 1.6	3.2 2.2	mA	$dr = 1$ Mbps, $R_L = 60\Omega$; $V_{DD1} = 5$ V $dr = 1$ Mbps, $R_L = 60\Omega$; $V_{DD1} = 3.3$ V
Quiescent supply current (recessive)	I_{QVDD2}	3.5	7	12	mA	0 bps
Dynamic supply current (dominant)	I_{VD2}	26	52	70	mA	1 Mbps, $R_L = 60\Omega$
Transmitter Data input (TxD)⁽¹⁾						
High level input voltage \uparrow	V_{IH}	2.4		5.25	V	$V_{DD1} = 5$ V; recessive
High level input voltage \uparrow	V_{IH}	2.0		3.6	V	$V_{DD1} = 3.3$ V; recessive
Low level input voltage \downarrow	V_{IL}	-0.3		0.8	V	Output dominant
TxD input rise and fall time ⁽²⁾	t_r			1	μ s	10% to 90% 
High level input current	I_{IH}	-10		10	μ A	$V_{TXD} = V_{DD1}$
Low level input current	I_{IL}	10		10	μ A	$V_{TXD} = 0$ V
Receiver Data output (RxD)						
High level output current	I_{OH}	-2	-8.5	-20	mA	$V_{RXD} = 0.8 V_{DD1}$
Low level output current	I_{OL}	2	8.5	20	mA	$V_{RXD} = 0.45$ V
Failsafe supply voltage ⁽⁴⁾	V_{DD2}	3.6		3.9	V	
Bus lines (CANH and CANL)						
Recessive voltage at CANH pin	$V_{O(rec)} CANH$	2.0	2.5	3.0	V	$V_{TXD} = V_{DD1}$, no load
Recessive voltage at CANL pin	$V_{O(rec)} CANL$	2.0	2.5	3.0	V	$V_{TXD} = V_{DD1}$, no load
Recessive current at CANH pin	$I_{O(rec)} CANH$	-2.5		+2.5	mA	$-27V < V_{CANH} < +32V$; $0V < V_{DD2} < 5.25V$
Recessive current at CANL pin	$I_{O(rec)} CANL$	-2.5		+2.5	mA	$-27V < V_{CANL} < +32V$; $0V < V_{DD2} < 5.25V$
Dominant voltage at CANH pin	$V_{O(dom)} CANH$	3.0	3.6	4.25	V	$V_{TXD} = 0$ V
Dominant voltage at CANL pin	$V_{O(dom)} CANL$	0.5	1.4	1.75	V	$V_{TXD} = 0$ V
Differential bus input voltage ($V_{CANH} - V_{CANL}$)	$V_{i(dif)(bus)}$	1.5	2.25	3.0	V	$V_{TXD} = 0$ V; dominant $42.5 \Omega < R_L < 60 \Omega$
		-120	0	+50	mV	$V_{TXD} = V_{DD1}$; recessive; no load
Short-circuit output current at CANH	$I_{O(sc)} CANH$	-45	-70	-95	mA	$V_{CANH} = 0$ V, $V_{TXD} = 0$
Short-circuit output current at CANL	$I_{O(sc)} CANL$	45	70	120	mA	$V_{CANL} = 36$ V, $V_{TXD} = 0$
Differential receiver threshold voltage	$V_{i(dif)(th)}$	0.5	0.7	0.9	V	$-5V < V_{CANL} < +10V$; $-5V < V_{CANH} < +10V$
Differential receiver input voltage hysteresis	$V_{i(dif)(hys)}$	50	70	100	mV	$-5V < V_{CANL} < +10V$; $-5V < V_{CANH} < +10V$
Common Mode input resistance at CANH	$R_{i(CM)(CANH)}$	15	25	37	k Ω	
Common Mode input resistance at CANL	$R_{i(CM)(CANL)}$	15	25	37	k Ω	
Matching between Common Mode input resistance at CANH, CANL	$R_{i(CM)(m)}$	-3	0	+3	%	$V_{CANL} = V_{CANH}$
Differential input resistance	$R_{i(dif)}$	25	50	75	k Ω	
Input capacitance, CANH	$C_{i(CANH)}$		7.5	20	pF	$V_{TXD} = V_{DD1}$
Input capacitance, CANL	$C_{i(CANL)}$		7.5	20	pF	$V_{TXD} = V_{DD1}$
Differential input capacitance	$C_{i(dif)}$		3.75	10	pF	$V_{TXD} = V_{DD1}$
Input leakage current at CANH	$I_{LI(CANH)}$	100	170	250	μ A	$V_{CANH} = 5$ V, $V_{DD2} = 0$
Input leakage current at CANL	$I_{LI(CANL)}$	100	170	250	μ A	$V_{CANL} = 5$ V, $V_{DD2} = 0$
Thermal Shutdown						
Shutdown junction temperature	$T_{j(SD)}$	155	165	180	$^{\circ}$ C	

Timing Characteristics (60 Ω / 100 pF bus loading; 20 pF RxD load; see Fig. 1)

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
TxD to bus active delay	$t_{d(TxD-BUSon)}$	44 36	93 96	160 128	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
TxD to bus inactive delay	$t_{d(TxD-BUSoff)}$	34 37	68 71	110 113	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Bus active to RxD delay	$t_{d(BUSon-RxD)}$	29 32	63 66	125 128	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Bus inactive to RxD delay	$t_{d(BUSoff-RxD)}$	69 72	108 111	170 173	ns	$V_S = 0\text{ V}; V_{DD1} = 5\text{ V}$ $V_S = 0\text{ V}; V_{DD1} = 3.3\text{ V}$
Loop delay low-to-high or high-to-low	T_{LOOP}	74	180	210	ns	$V_S = 0\text{ V}$; "Typ." at 25°C and nominal loads
TxD dominant time for timeout	$T_{dom(TxD)}$	250	457	765	μs	$V_{TxD} = 0\text{ V}$ $3.0\text{ V} > V_{DD1} < 5.5\text{ V}$
Common Mode Transient Immunity (TxD Logic High or Logic Low)	$ ICM_{HL} , ICM_{LL} $	30	50		kV/μs	$R_L = 60\text{ Ω}$; $V_{CM} = 1500\text{ V}_{DC}$; $t_{TRANSIENT} = 25\text{ ns}$

Magnetic Field Immunity⁽³⁾ ($V_{DD2} = 5\text{ V}, 3\text{ V} < V_{DD1} < 5.5\text{ V}$)

Power Frequency Magnetic Immunity	H_{PF}		6000		A/m	50Hz/60Hz
Pulse Magnetic Field Immunity	H_{PM}		7000		A/m	$t_p = 8\text{ μs}$
Damped Oscillatory Magnetic Field	H_{OSC}		7000		A/m	0.1Hz – 1MHz
Cross-axis Immunity Multiplier	K_X		2			See Fig. 4

Insulation Specifications

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Creepage distance (external)		8.03	8.3		mm	Per IEC 60601
Total barrier thickness (internal)		0.012	0.013		mm	
Barrier resistance	R_{IO}		$>10^{14}$		Ω	500 V
Barrier capacitance	C_{IO}		7		pF	$f = 1\text{ MHz}$
Leakage current			0.2		μA _{RMS}	240 V _{RMS} , 60 Hz
Comparative Tracking Index	CTI	≥175			V	Per IEC 60112
High voltage endurance (maximum barrier voltage for indefinite life)	AC	V_{IO}	1000		V _{RMS}	At maximum operating temperature
	DC		1500		V _{DC}	
Barrier life			44000		Years	100°C, 1000 V _{RMS} , 60% CL activation energy

Thermal Characteristics

Parameter	Symbol	Min.	Typ.	Max.	Units	Test Conditions
Junction–Ambient Thermal Resistance	θ_{JA}		67		°C/W	Double-sided PCB in free air
Junction–Case (Top) Thermal Resistance	θ_{JC}		12			
Junction–Ambient Thermal Resistance	θ_{JA}		46			2s2p PCB in free air per JESD51
Junction–Case (Top) Thermal Resistance	θ_{JC}		9			
Power Dissipation	P_D			1500	mW	

Notes:

- The TxD input is edge sensitive. Voltage magnitude of the input signal is specified, but edge rate specifications must also be met.
- The maximum time allowed for a logic transition at the TxD input is 1 μs.
- Test and measurement methods are given in the Electromagnetic Compatibility section on p. 10.
- If V_{DD2} falls below the specified failsafe supply voltage, RxD will go High.

Timing Test Circuit

Timing parameters are measured with $60\ \Omega$ / $100\ \text{pF}$ bus line loading and $20\ \text{pF}$ on RxD as shown in Figure 1 below:

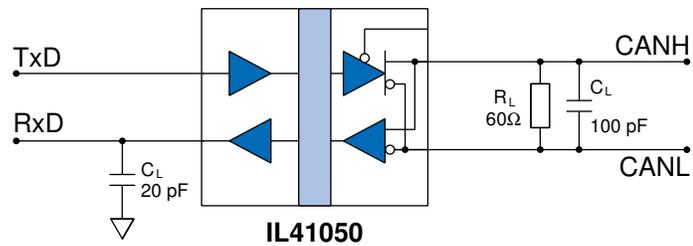


Figure 1. Timing characteristics test circuit.

Block Diagram

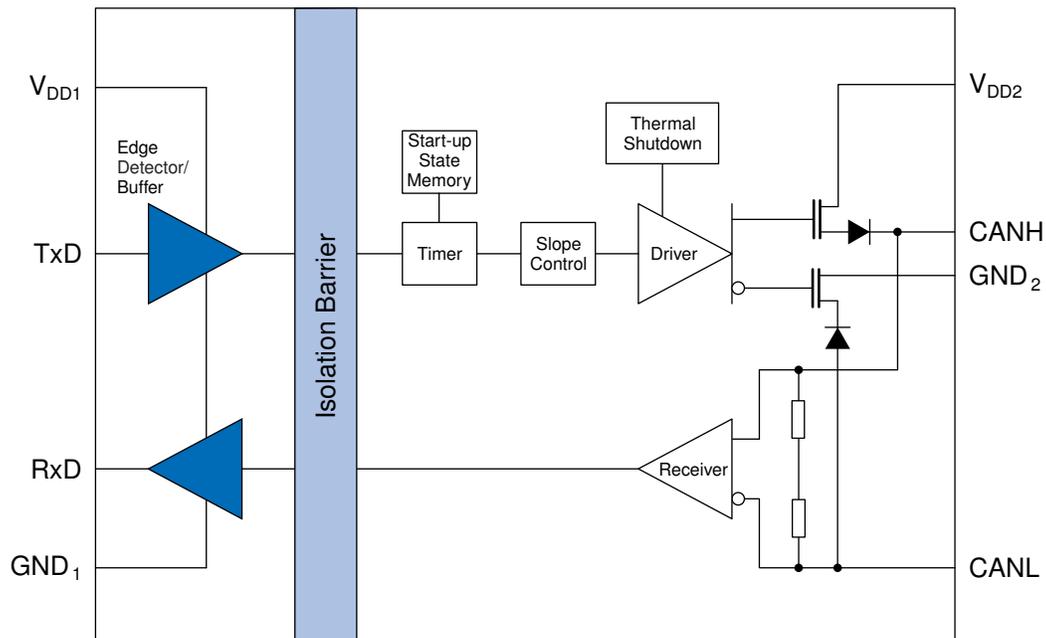


Figure 2. IL41050TT detailed functional diagram.

Application Information

As Figure 3 shows, the IL41050TT can provide isolation and level shifting between a 5 volt CAN bus and a 3 volt microcontroller:

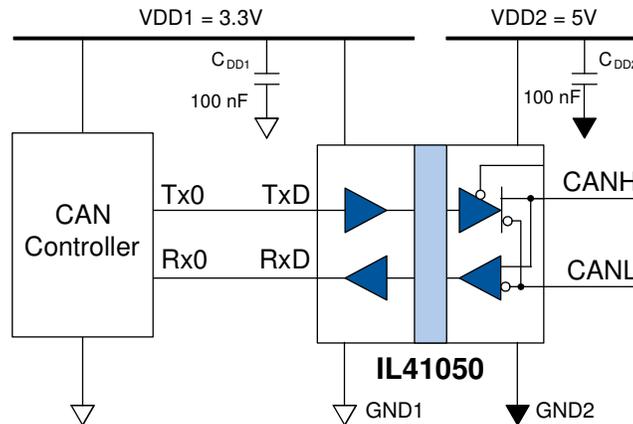


Figure 3. Isolated CAN node using the IL41050TT.

Power Supply Decoupling

V_{DD1} and V_{DD2} should be bypassed with 0.1 μF typical (0.047 μF minimum) capacitors as close as possible to the V_{DD} pins.

Maintaining Creepage

Creepage distances are often critical in isolated circuits. In addition to meeting JEDEC standards, NVE isolator packages have unique creepage specifications. Standard pad libraries often extend under the package, compromising creepage and clearance. Similarly, ground planes, if used, should be spaced to avoid compromising clearance. Package drawings and recommended pad layouts are included in this datasheet.

Input Configurations

The TxD input should not be left open as the state will be indeterminate. If connected to an open-drain or open collector output, a pull-up resistor (typically 16 k Ω) should be connected from the input to V_{DD1} .

Dominant Mode Time-out and Failsafe Receiver Functions

CAN bus latch up is prevented by an integrated Dominant mode timeout function. If the TxD pin is forced permanently low by hardware or software application failure, the time-out returns the RxD output to the high state no more than 765 μs after TxD is asserted dominant. The timer is triggered by a negative edge on TxD. If the duration of the low is longer than the internal timer value, the transmitter is disabled, driving the bus to the recessive state. The timer is reset by a positive edge on pin TxD.

If power is lost on V_{dd2} , the IL41050 asserts the RxD output high when the supply voltage falls below 3.8 V. RxD will return to normal operation when V_{dd2} rises above approximately 4.2 V.

Programmable Power-Up

A unique non-volatile programmable power-up feature prevents unstable nodes. A state that needs to be present at node power up can be programmed at the last power down. For example if a CAN node is required to “pulse” dominant at power up, TxD can be sent low by the controller immediately prior to power down. When power is resumed, the node will immediately go dominant allowing self-check code in the microcontroller to verify node operation. If desired, the node can also power up silently by presetting the TxD line high at power down. At the next power on, the IL41050 will remain silent, awaiting a dominant state from the bus.

The microcontroller can check that the CAN node powered down correctly before applying power at the next “power on” request. If the node powered down as intended, RxD will be set high and stored in the IL41050’s non-volatile memory. The level stored in the RxD bit can be read before isolated node power is enabled, avoiding possible CAN bus disruption due to an unstable node.

Replacing Non-Isolated CAN Transceivers

The IL41050 is designed to replace common non-isolated CAN transceivers such as the Philips/NXP TJA1050 with minimal circuit changes. Some notable differences:

- Some non-isolated CAN transceivers have internal TxD pull-up resistors, but the IL41050 TxD input should not be left open. If connected to an open-drain or open collector output, a pull-up resistor (typically 16 k Ω) should be connected from the input to V_{DD1}.
- Initialization behavior varies between CAN transceivers. To ensure the desired power-up state, the IL41050 should be initialized with a TxD pulse (low-to-high for recessive initialization), or shut down the transceiver in the desired power-up state (the “programmable power-up feature”).
- Many non-isolated CAN transceivers have a “sleep mode” select input (“S”) or V_{REF} output. These pins are not available on the IL41050TT. Please select the NVE IL41050TA if these pins are required.

Replacing Other Isolated CAN Transceivers

The IL41050TT is a pin-for-pin direct replacement for the Texas Instruments ISO1050DW Isolated CAN Transceiver, with advantages of much better reliability and longer barrier life, less EMI emissions, and true 8 mm external creepage per IEC 60601.

Electrostatic Discharge Sensitivity

This product has been tested for electrostatic sensitivity to the limits stated in the specifications. However, NVE recommends that all integrated circuits be handled with appropriate care to avoid damage. Damage caused by inappropriate handling or storage could range from performance degradation to complete failure.

Electromagnetic Compatibility

The IL41050 is fully compliant with IEC 61000-6-1 and IEC 61000-6-2 standards for immunity, and IEC 61000-6-3, IEC 61000-6-4, CISPR, and FCC Class A standards for emissions.

Immunity to external magnetic fields is higher if the field direction is “end-to-end” (rather than to “pin-to-pin”) as shown in the diagram below:

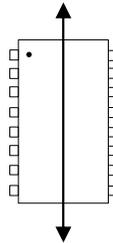
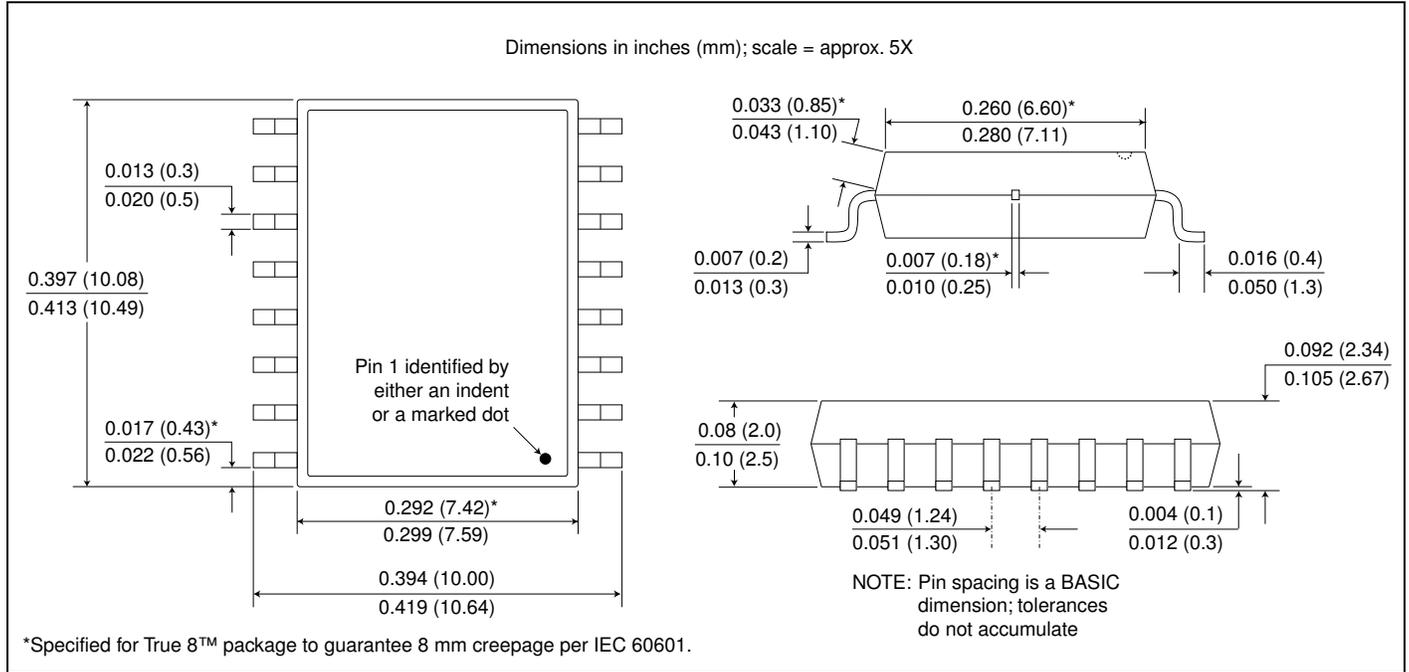
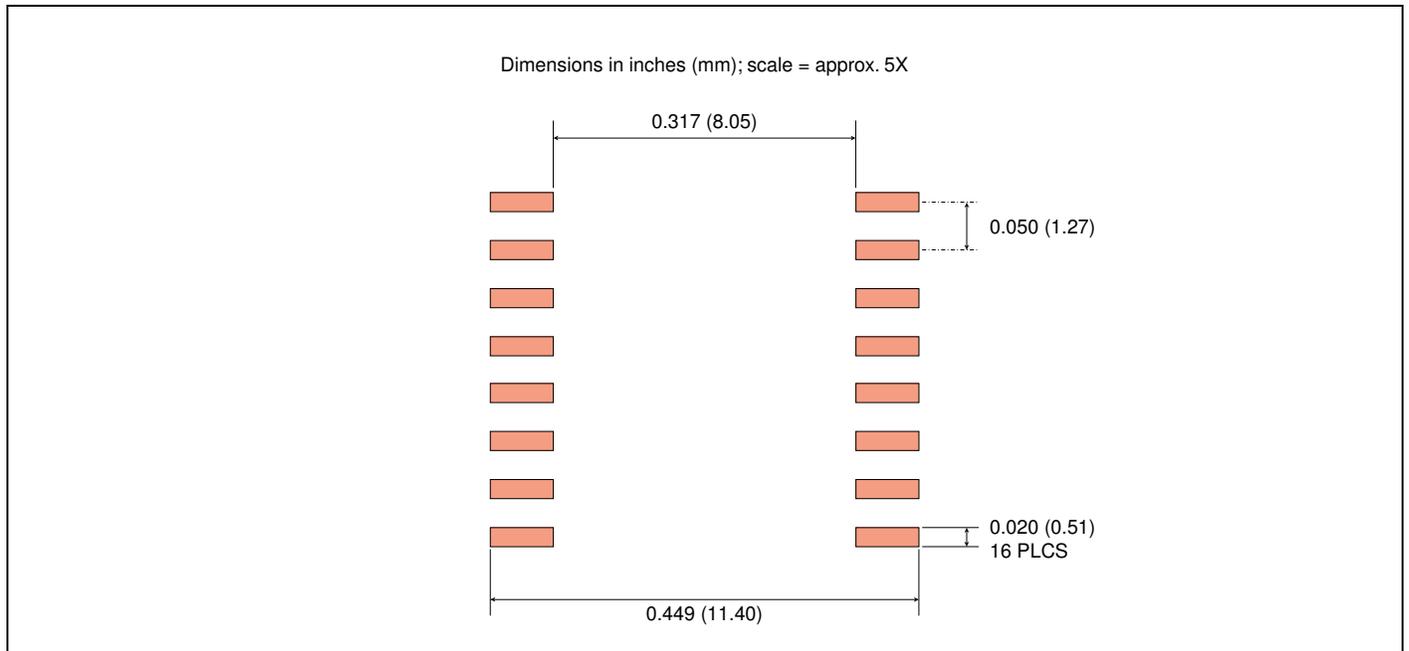


Figure 4. Orientation for high field immunity.

Package Drawing

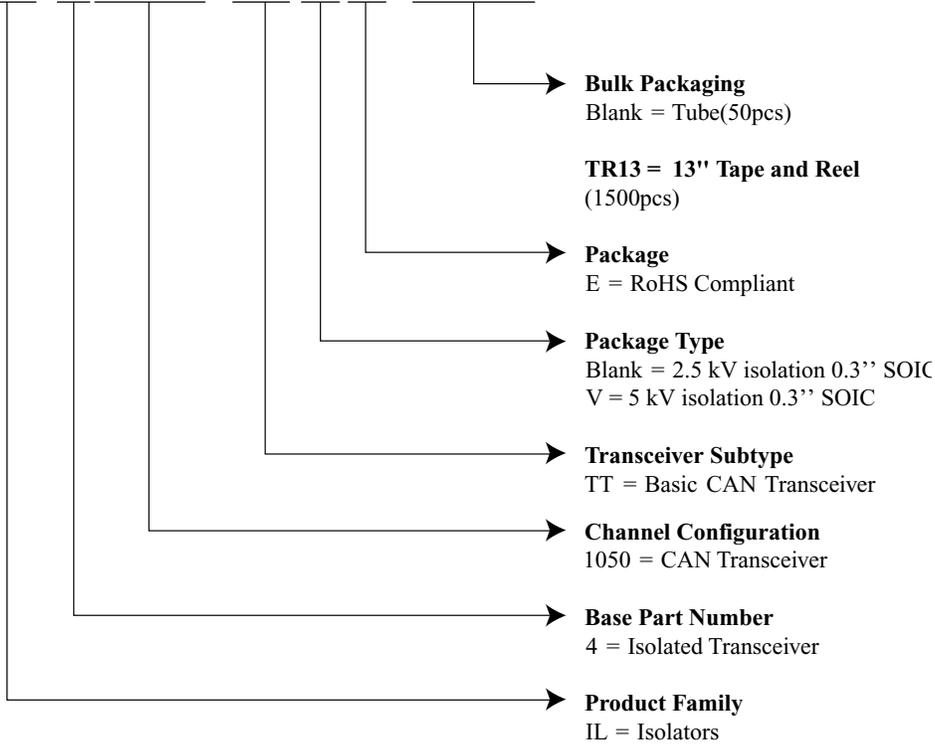


Recommended Pad Layout



Ordering Information

IL 41050 TTVE TR13



Revision History

ISB-DS-001-IL41050TT-B

August 2022

Changes

- Upgraded VDE approval to IEC 60747-17 (VDE 0884-17):2021-10 (p. 3).
- Upgrade “V” version from basic to reinforced isolation (p. 3).
- Increased Working Voltage ratings based on latest VDE testing (p. 3).
- Updated EMC standards.
- Deleted minimum magnetic immunity specifications (p. 6) since it is not 100% tested.
- Improved thermal characteristics (p. 6).

ISB-DS-001-IL41050TT-A

November 2015

Changes

- Added 2.5 kV isolation version.
- Initial Release at Rev. A.

ISB-DS-001-IL41050TT-PRELIM-3

October 2015

Changes

- Deleted non-applicable specification sections on p. 5.

ISB-DS-001-IL41050TT-PRELIM-2

September 2015

Changes

- Updated pin descriptions on p. 4.

ISB-DS-001-IL41050TT-PRELIM

September 2015

Preliminary Release

Datasheet Limitations

The information and data provided in datasheets shall define the specification of the product as agreed between NVE and its customer, unless NVE and customer have explicitly agreed otherwise in writing. All specifications are based on NVE test protocols. In no event however, shall an agreement be valid in which the NVE product is deemed to offer functions and qualities beyond those described in the datasheet.

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Applications described in this datasheet are illustrative only. NVE makes no representation or warranty that such applications will be suitable for the specified use without further testing or modification.

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